

8053-1008  
PATENT



IN THE U.S. PATENT AND TRADEMARK OFFICE

in re application of

Yuichi NAITOU et al.

Conf. 7712

Application No. 09/981,390

Group 2881

Filed October 18, 2001

Examiner Phillip Johnston

SCANNING PROBE MICROSCOPE WITH PROBE FORMED BY SINGLE  
CONDUCTIVE MATERIAL

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

April 5, 2004

Sir:

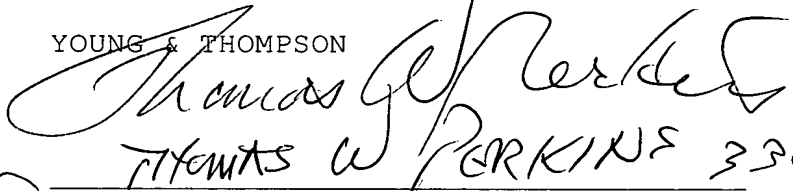
In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed Form PTO-1449.


A concise explanation of the relevance of these items is that these references were cited by the Japanese Patent Office in an Office Action of February 24, 2004 in the corresponding Japanese Application Serial No. 2000-317368, filed October 18, 2000. A copy of the Official Action in which they were cited is attached hereto, with what is believed to be the pertinent portion enclosed in a wavy line. An English translation of the enclosed portion is also attached hereto.

Under the provisions of 37 CFR 1.97(e), the undersigned hereby certifies that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign Patent Office in a counterpart foreign application not more than three months prior to the filing of this Statement.

Respectfully submitted,

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RJP/mjr

April 5, 2004

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.  
8053-1008

SERIAL NO.  
09/981,390

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

CFR 1.98(b)

APPLICANT  
Yuichi NAITOU et al.

FILING DATE  
October 18, 2001

GROUP  
2881

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						

**FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION**

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
	AL	10-282121	10/98	Japan			Abst.
	AM	04-238203	8/92	Japan			Abst.
	AN	08-248043	9/96	Japan			Abst.
	AO	10-064965	3/98	Japan			Abst.
	AP	10-082790	3/98	Japan			Abst.
	AQ	2000-065716	3/2000	Japan			Abst.

**OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)**

	AR	
	AS	
	AT	

**EXAMINER**

**DATE CONSIDERED**

**EXAMINER:** Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

**FORM PTO-1449** U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

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(37 CFR 1.98(b))



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**FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION**

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
	AR	11-038029	2/1999	Japan			Abst.
	AS	09-329606	12/97	Japan			Abst.
	AT	07-229908	8/95	Japan			Abst.
	AU						
	AV						

**OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)**

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